

AMT Status

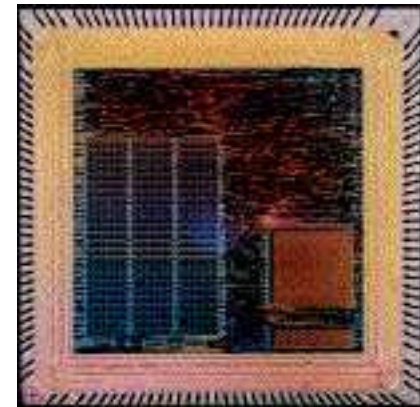
Yasuo Arai (KEK)

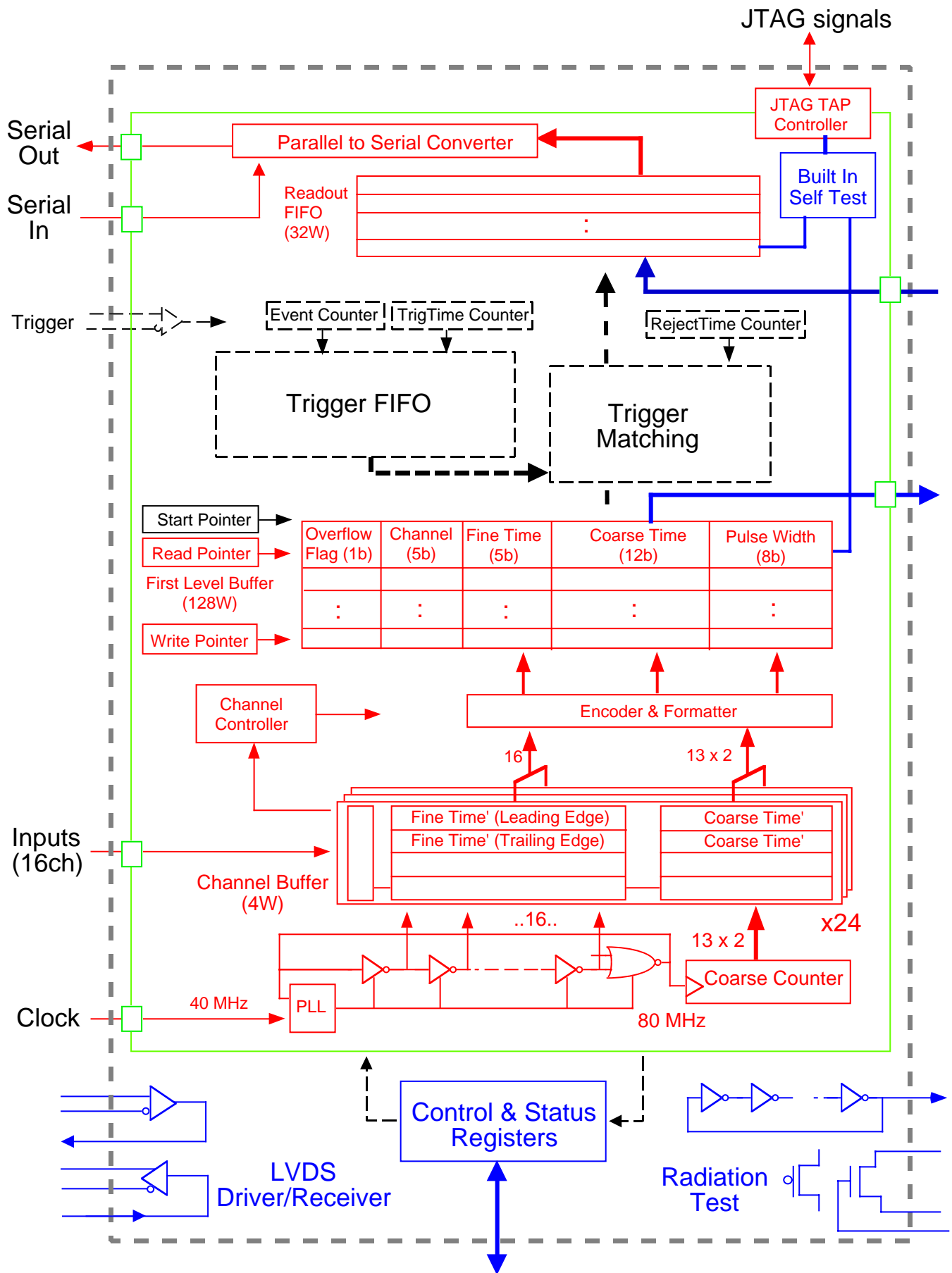
yasuo.arai@kek.jp

<http://atlas.kek.jp/~arai/>

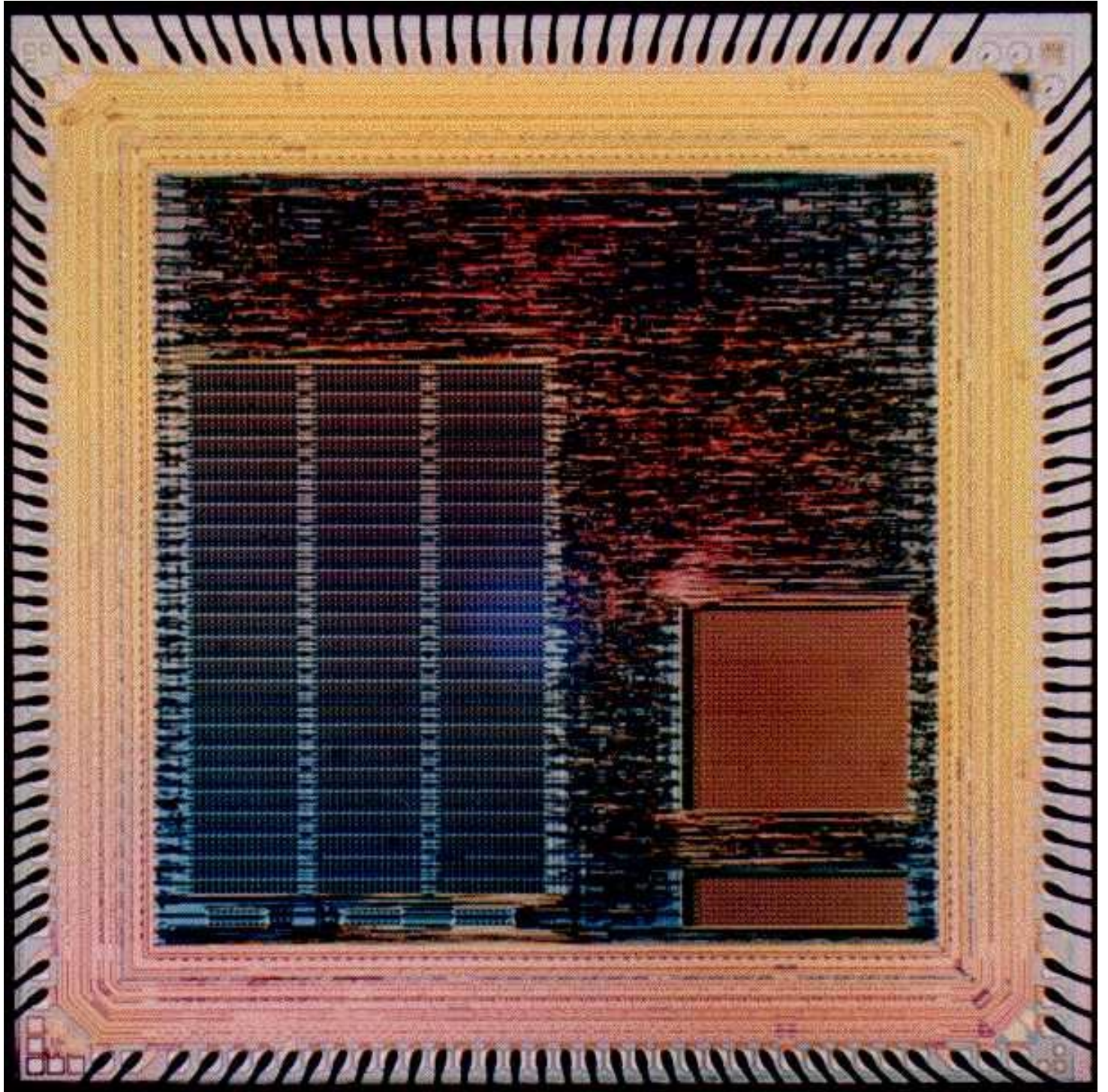
June 6, 1999
PC Elec@CERN

- AMT-TEG1 test
 - Previous measurements
 - New measurements
- AMT-1 schedule
- Summary





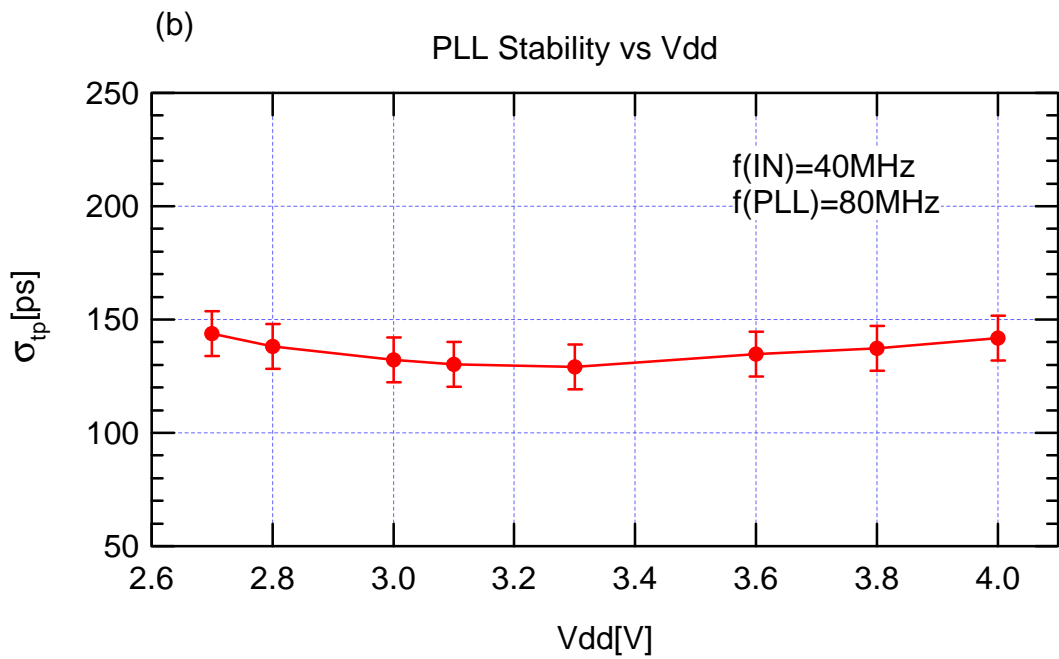
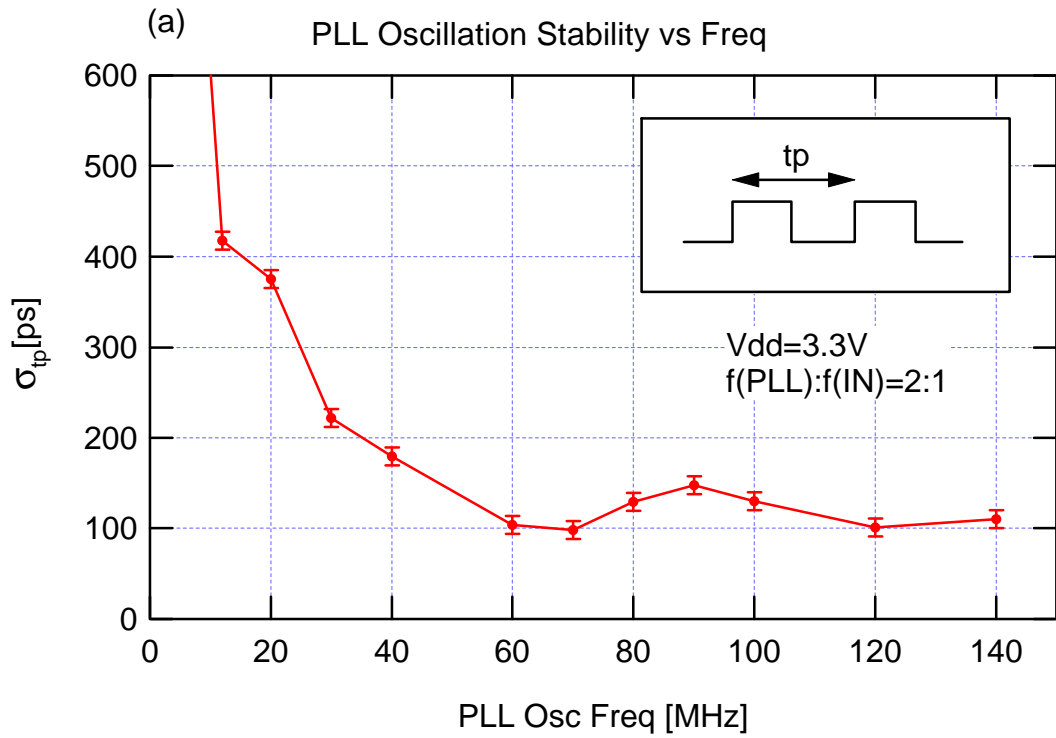
AMT-TEG1 Block Diagram

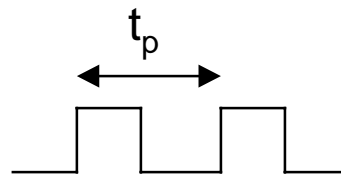


AMT-TEG1 test

- AMT-TEG1 is successfully designed in a 0.3 μm CMOS process.
- Reported measurements in previous meetings.

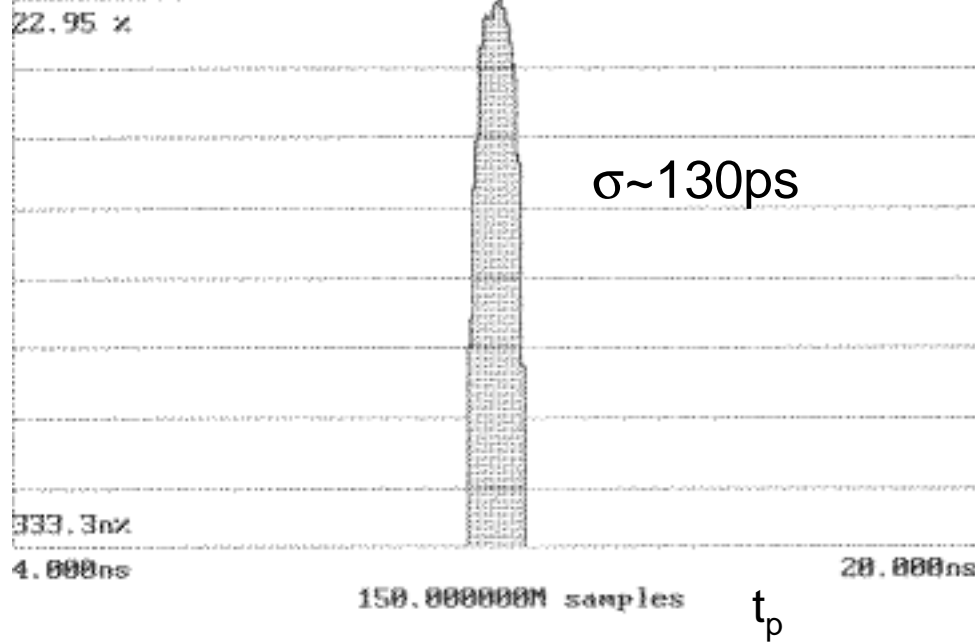
	measured value	operating point (target value)
PLL Operation	Freq = 40 ~ 120 MHz Vdd = 2.8 ~ 3.8V	80 MHz 3.3V
PLL Jitter	$\sigma \sim 130$ ps	< 200 ps
Coarse Time Counter	120 MHz	80 MHz
Radiation hardness for γ	50 krad	11 krad
Radiation hardness for n	to be measured (irradiated at April)	1.2×10^{13} n/cm ²





$f_{PLL} = 80 \text{ MHz}$
 $V_{dd} = 3.3 \text{ V}$

(hp) +TI Af+Bf tik only
 stopped

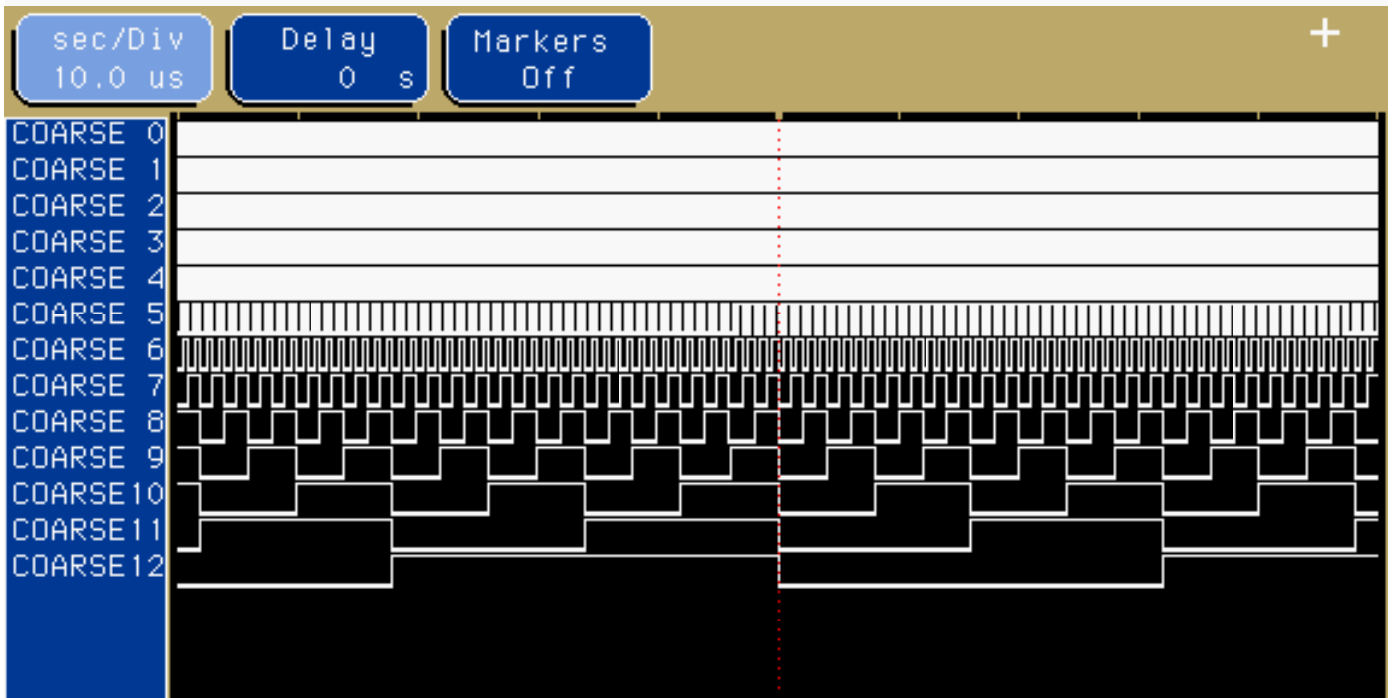
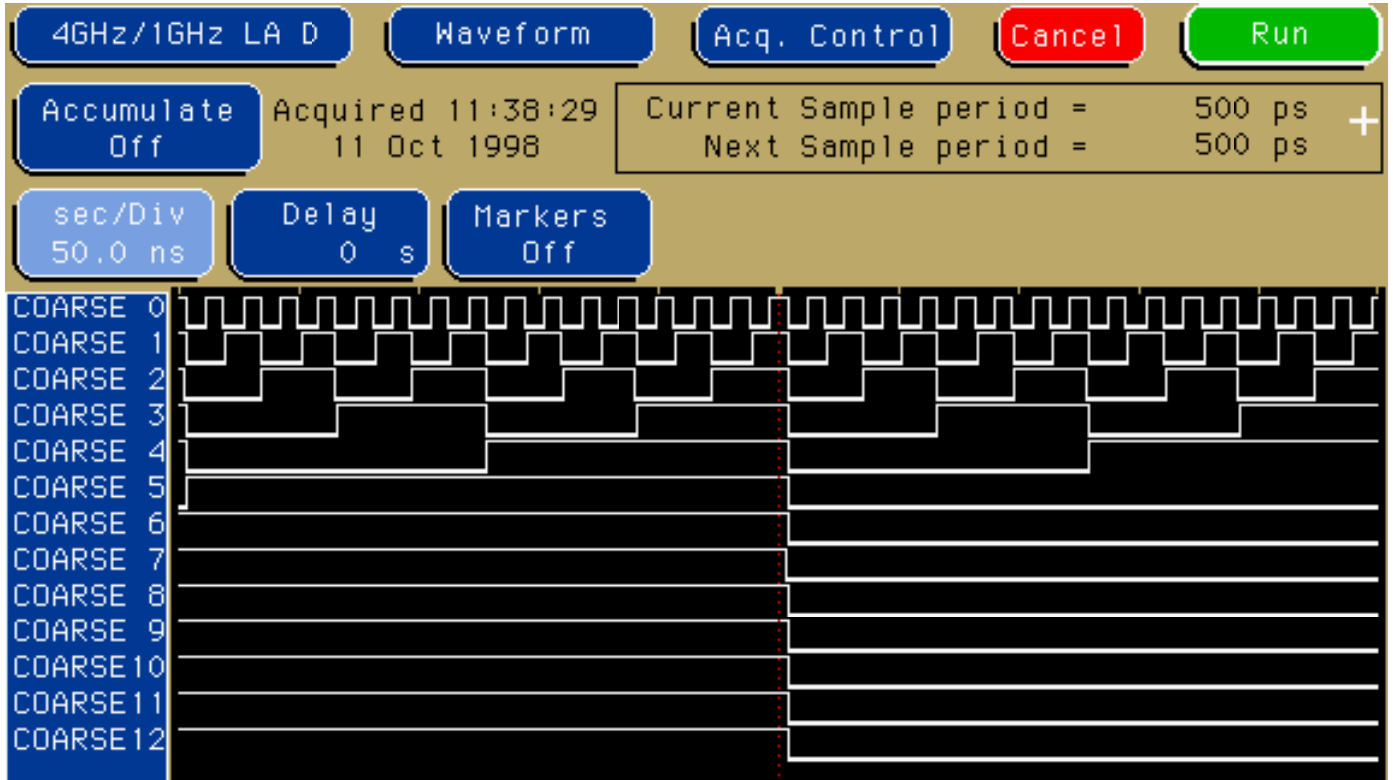
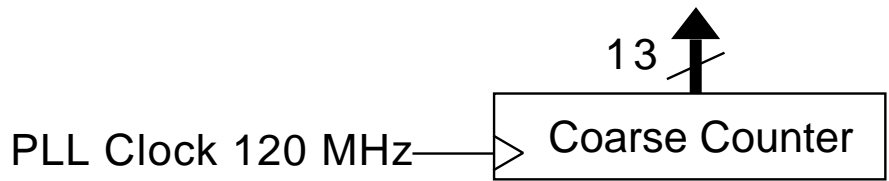


Mean 11.98597569ns

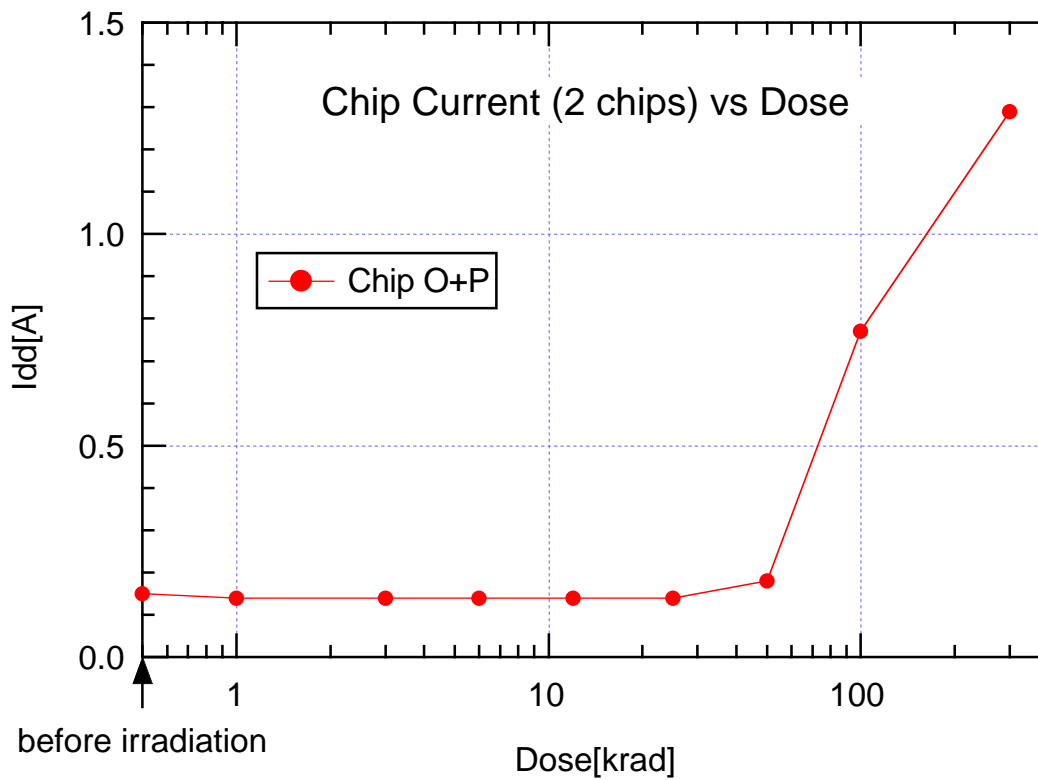
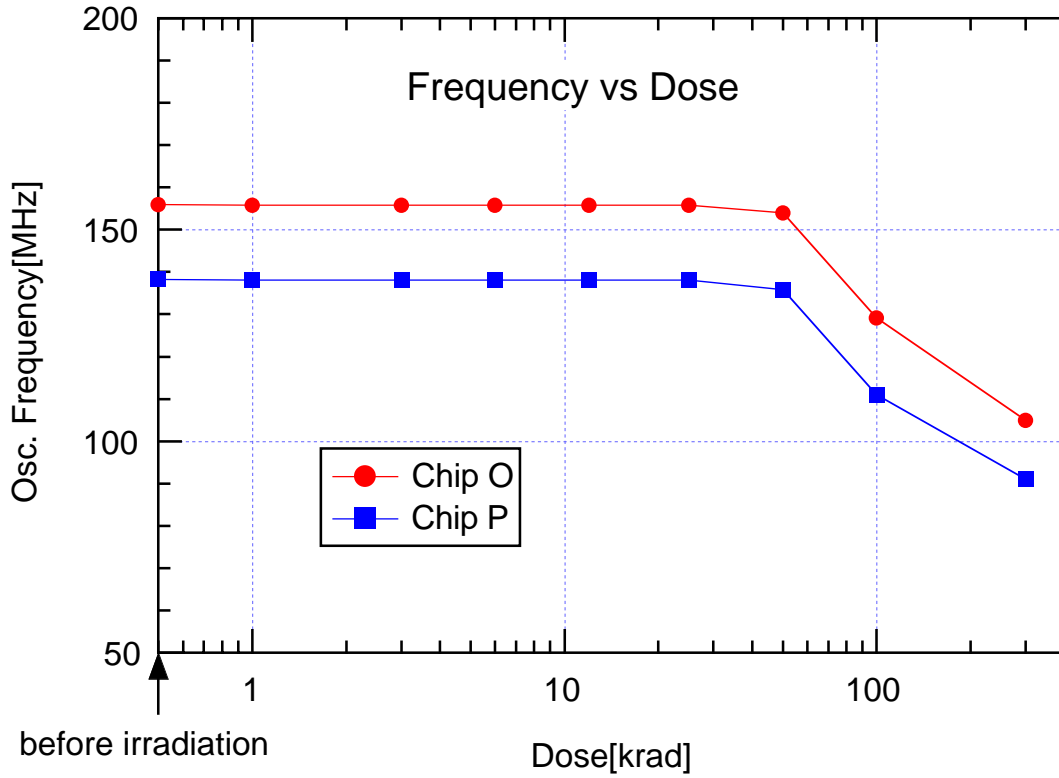
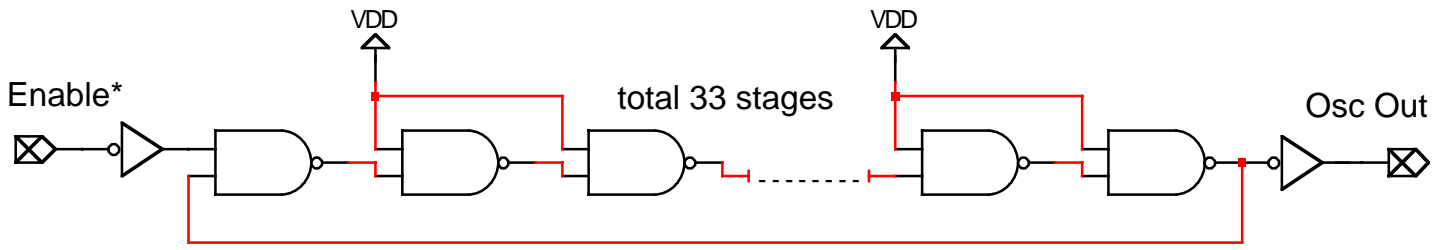
STATUS
 FUNC&INP TI,Com,
 f=f,+TI;
 A=92.50mV,DC,1Ma,
 Hyst=8%;B=
 92.50mV,DC,1Ma,
 Hyst=8%;X=TTL,1:1
 TIMEBASE
 Not available in
 FAST HIST mode
 TRIGGER
 Not available in
 FAST HIST mode
 HISTOGRAM
 Fast:On,Auto,
 Num=1000000,
 Acc:On
 SAMPLING Auto
 HP-1B Talk Only

PLL Oscillation Jitter Histogram

Coarse Time Counter



AMT-TEG1 Ring Oscillator

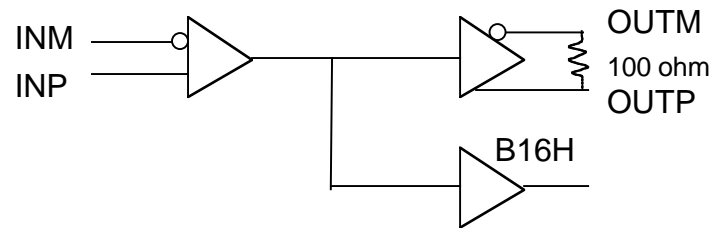


New Measurements

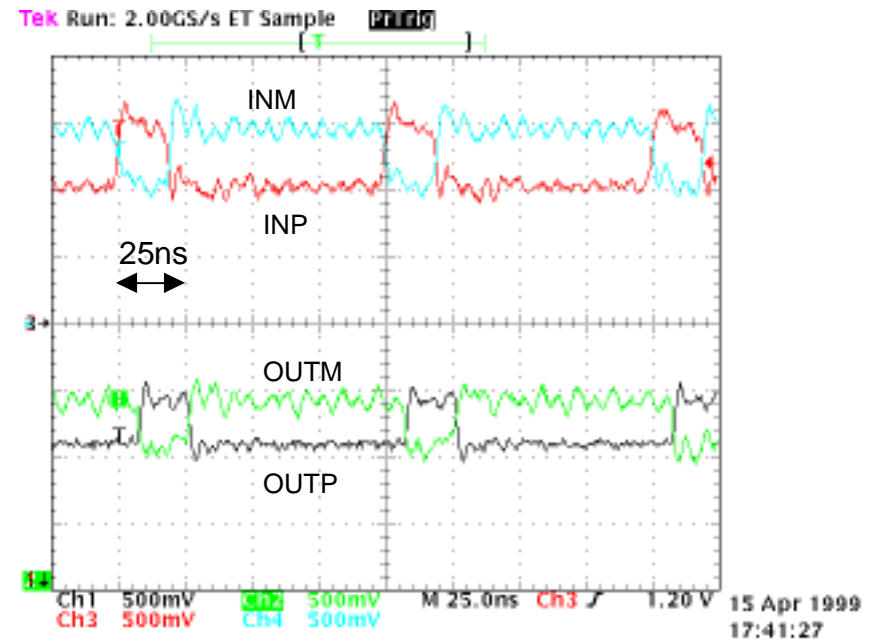
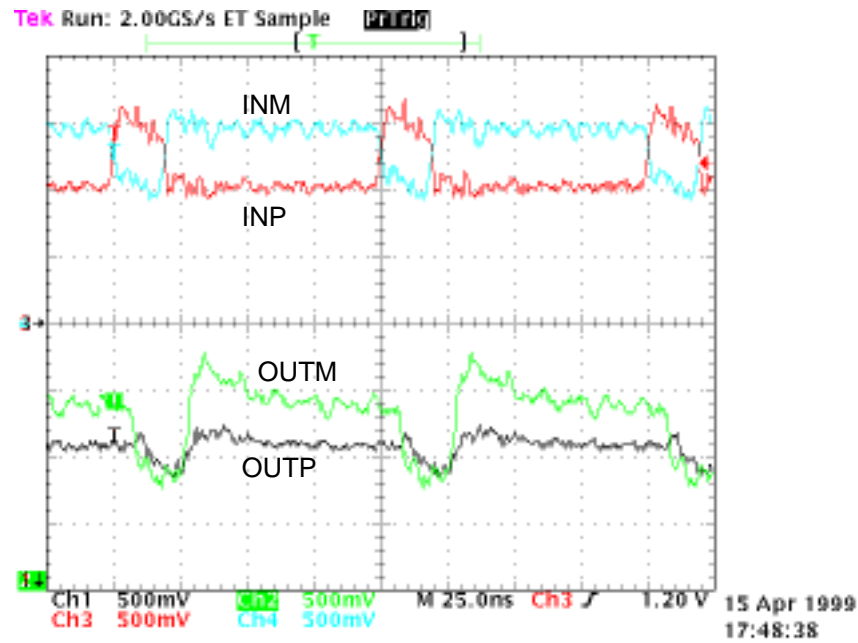
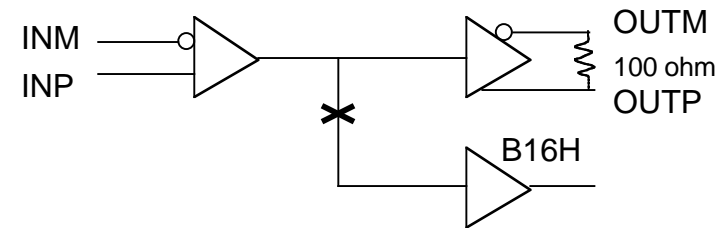
	measured value	operating point (target value)
LVDS receiver: ΔV V_{cm}	> 100 mV 0.2 ~ 2.2 V	> 100 mV 0.2 ~ 2.2V
LVDS driver (6.5m cable)	> 100 MHz	> 50MHz
Multiple edge resolution (double edge) (single edge)	5 ns 9 ns	30 ns 15 ns
L1B input speed	(2 + N) clocks	(4 + N) clocks
Time Resolution	305 ps RMS	< 500 ps RMS
Differential Nonlinearity	0.06 ns RMS	< 0.2 ns RMS
Integral Nonlinearity	0.07 ns RMS	< 0.2 ns RMS

AMT-TEG1 LVDS Test

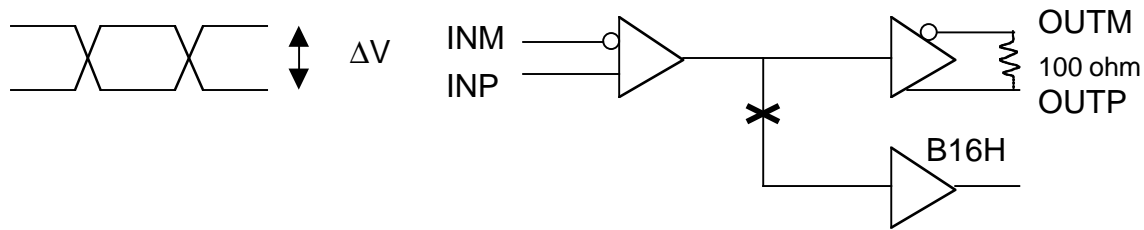
Chip0 (original)



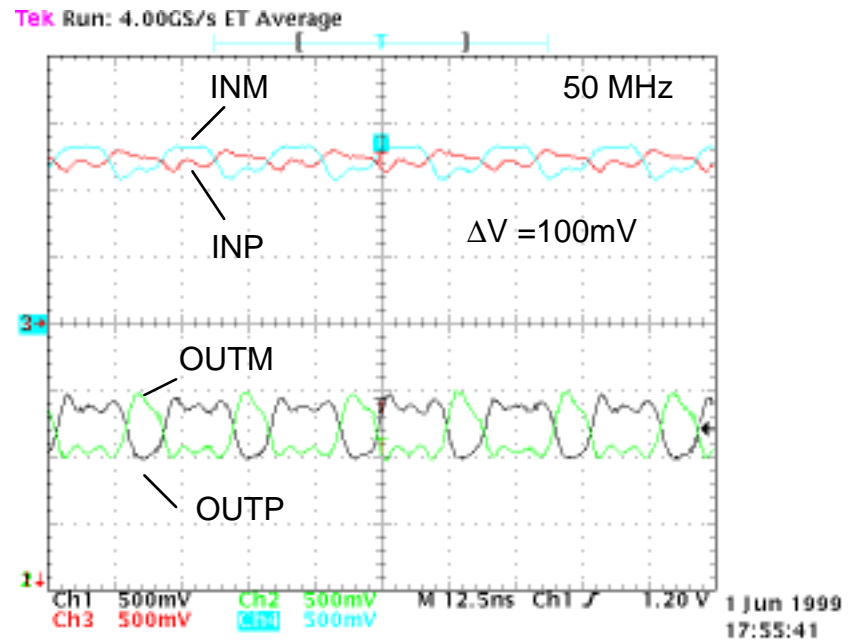
Chip1 (B16H cut)



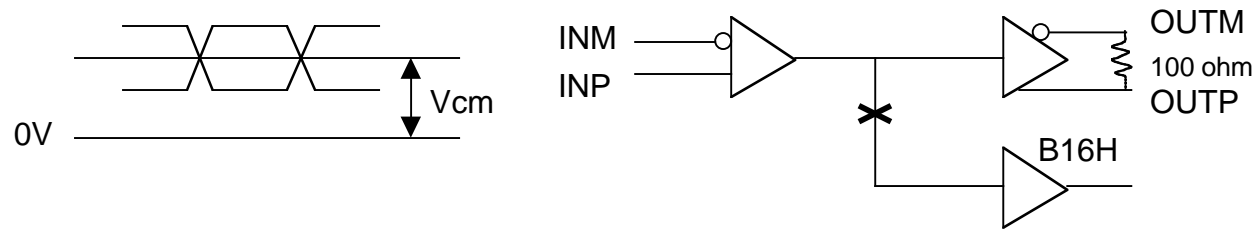
Receiver : Input Threshold ($V_{cm}=1.2V$)



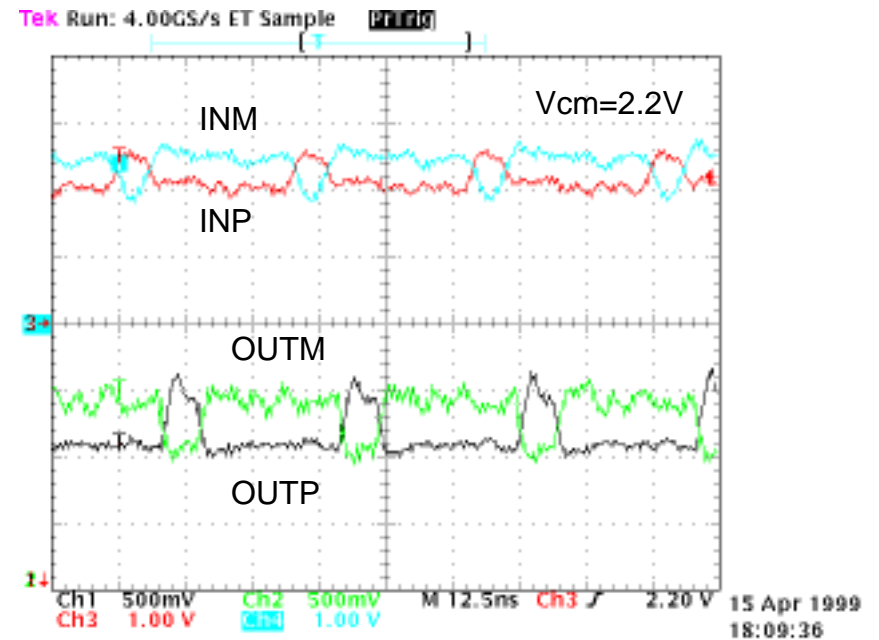
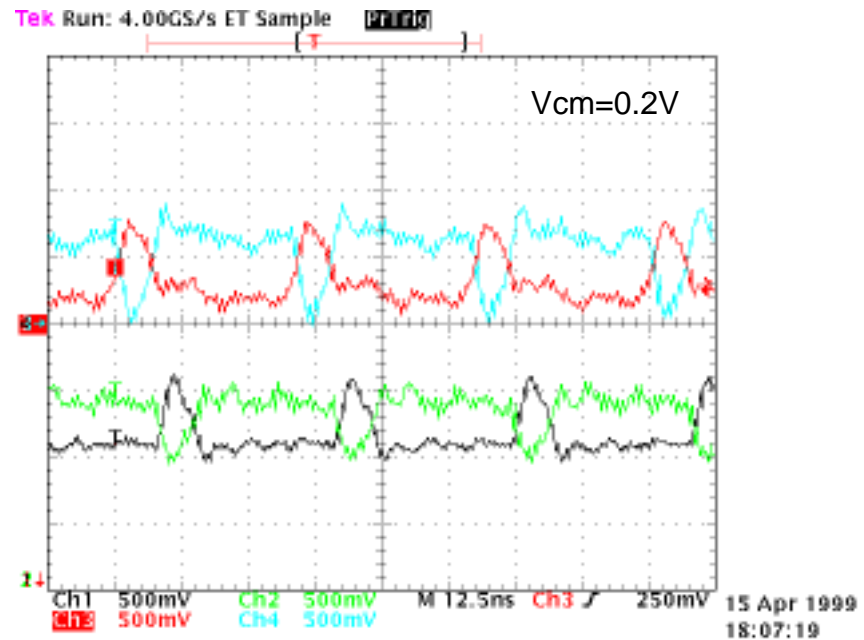
(IEEE 1596.3 spec : $|\Delta V| > 100 \text{ mV}$)



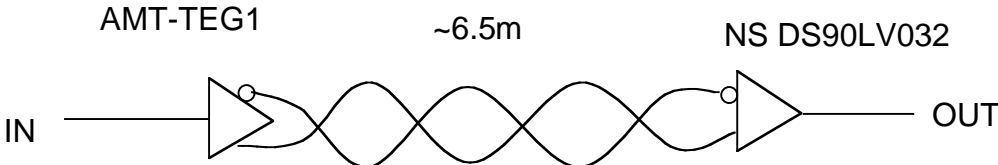
Central Voltage Dependence ($V_{id}=400\text{mV}$)



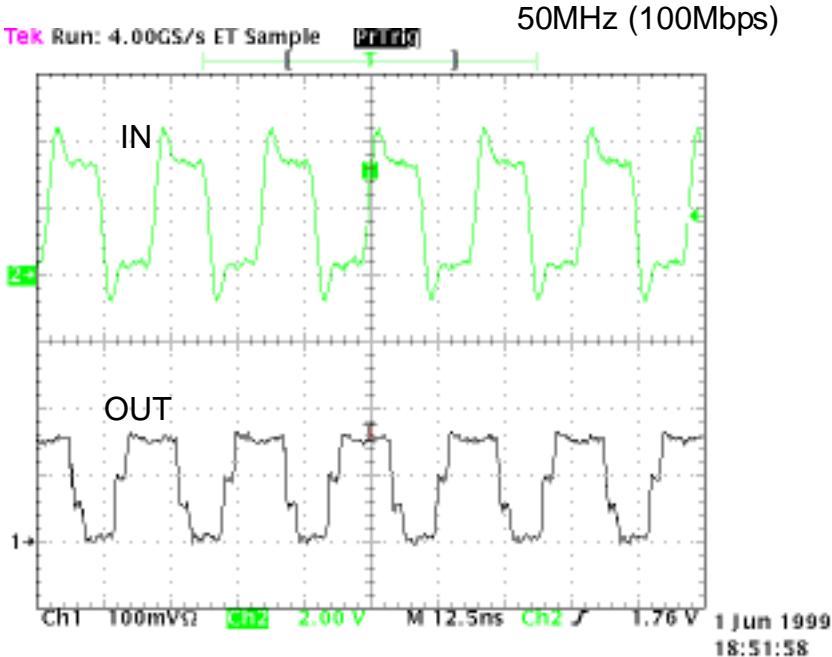
(IEEE 1596.3 spec : $0.2\text{V} < V_{cm} < 2.2\text{V}$)



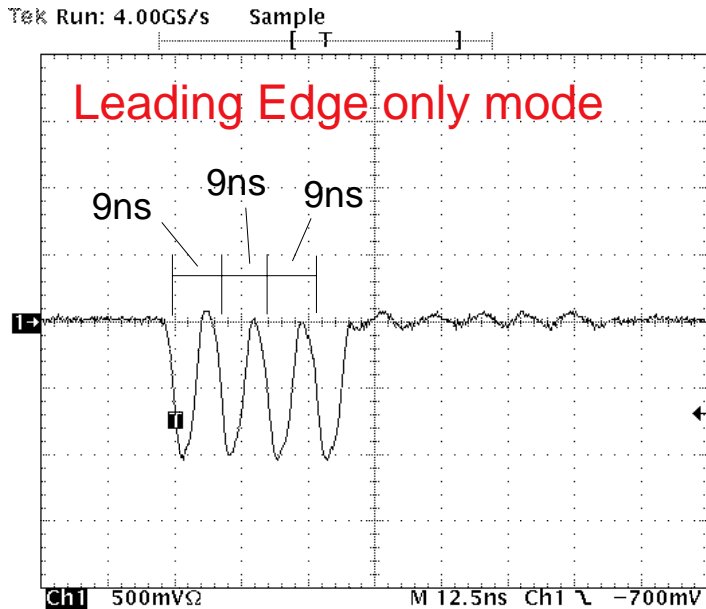
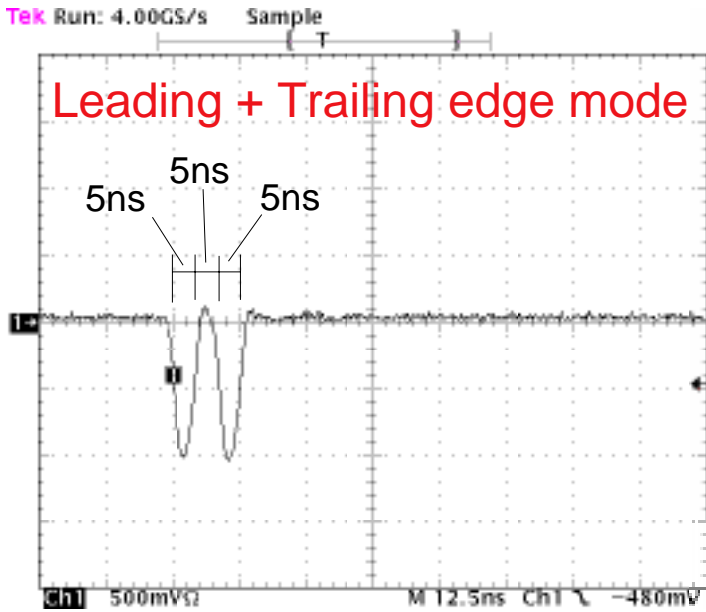
Long Cable Drive



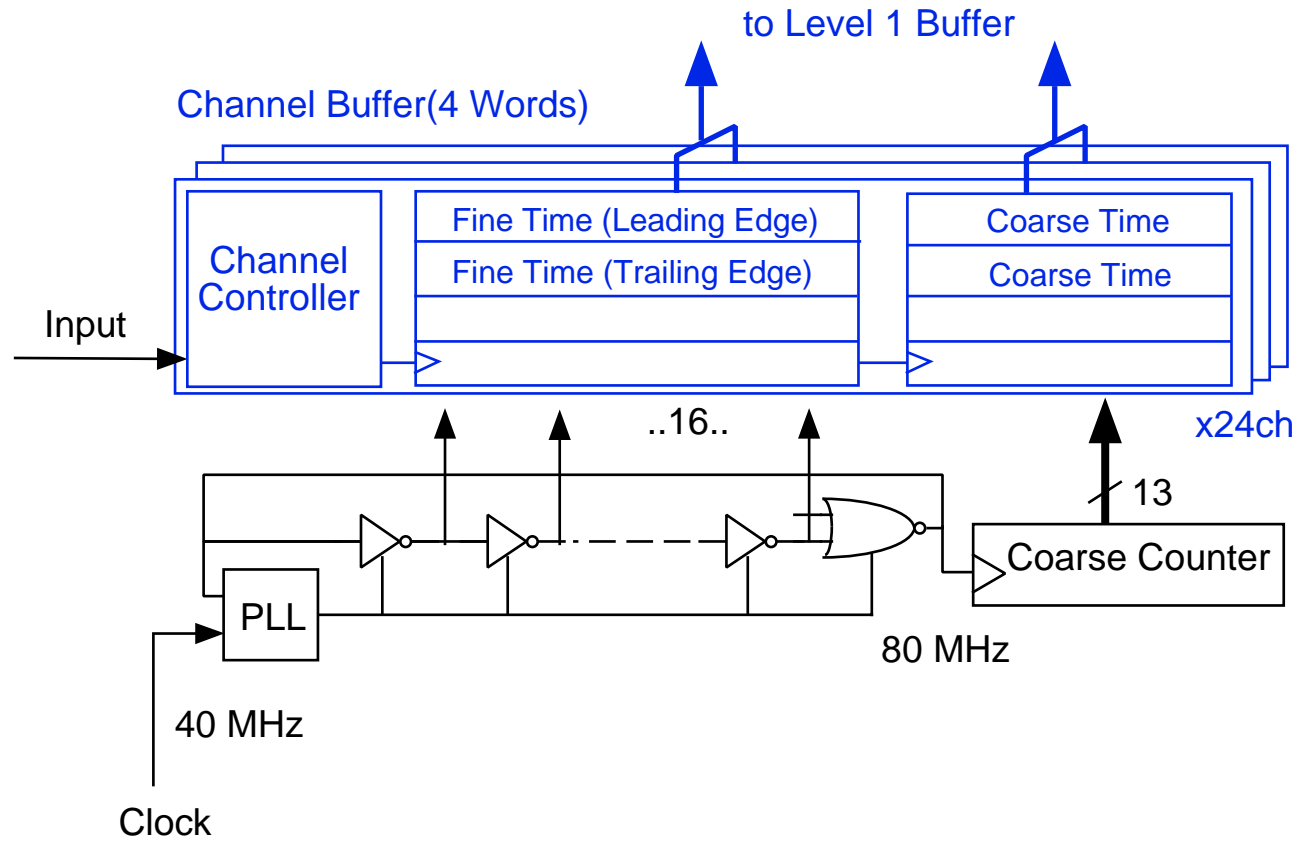
Maximum Frequency > 100MHz



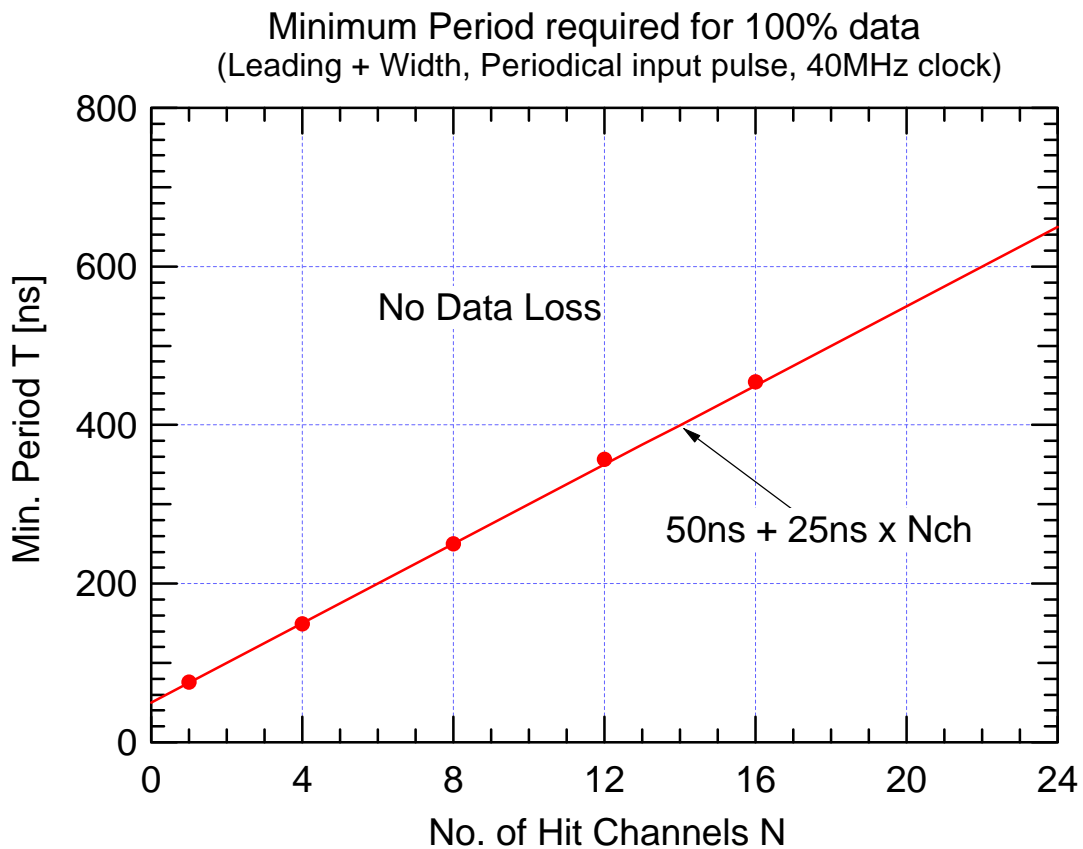
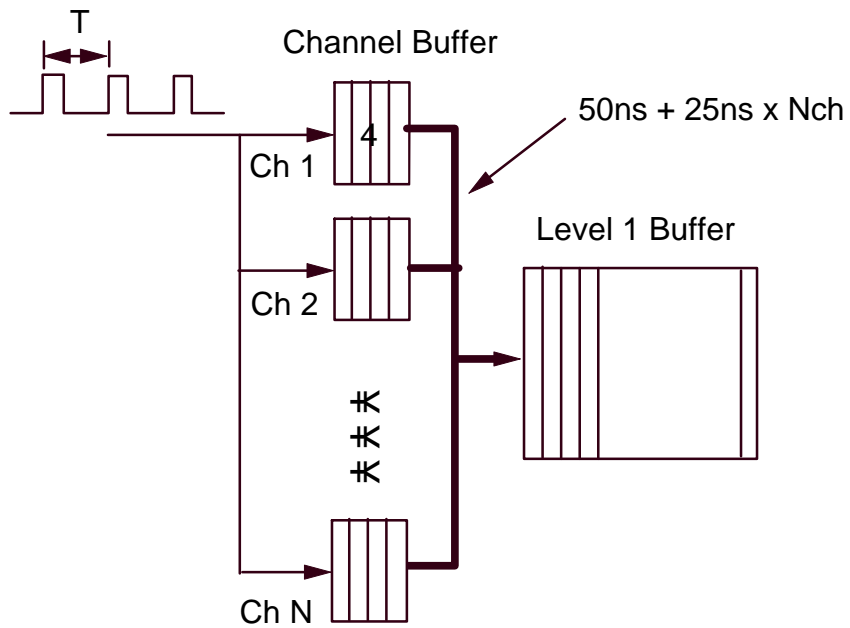
Channel Buffer Speed



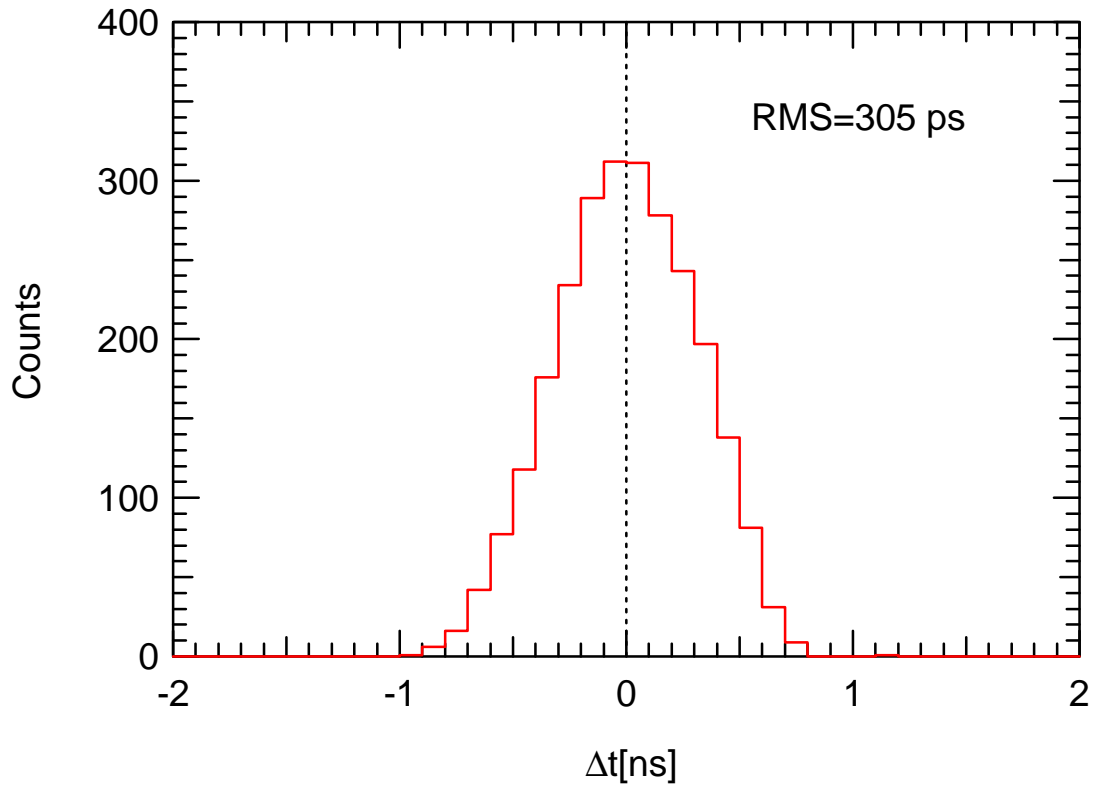
Multiple Edge Resolution = 5 ns (Double Edge)
= 9 ns (Single Edge)



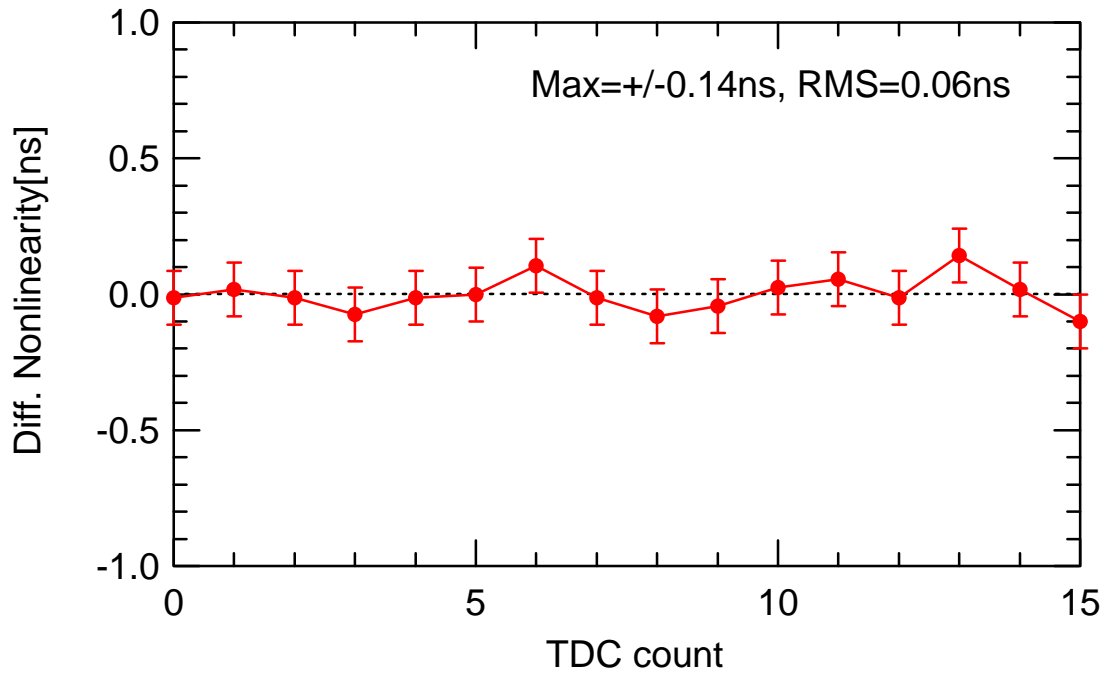
Data Transfer Rate to L1 Buffer



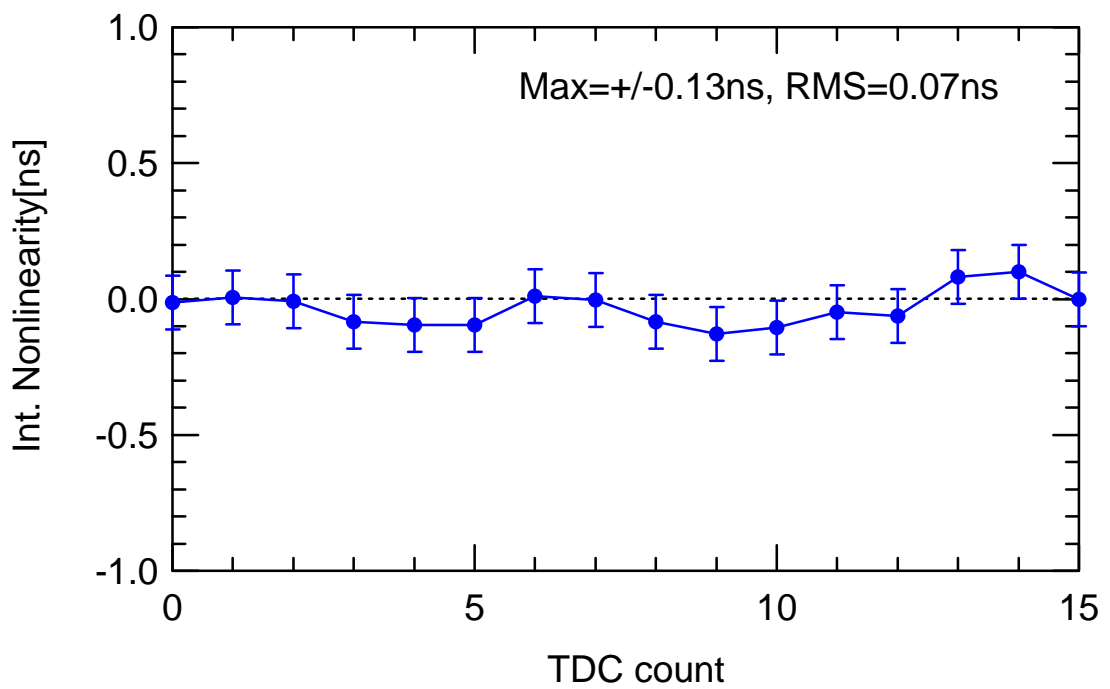
AMT-TEG1 Timing Resolution



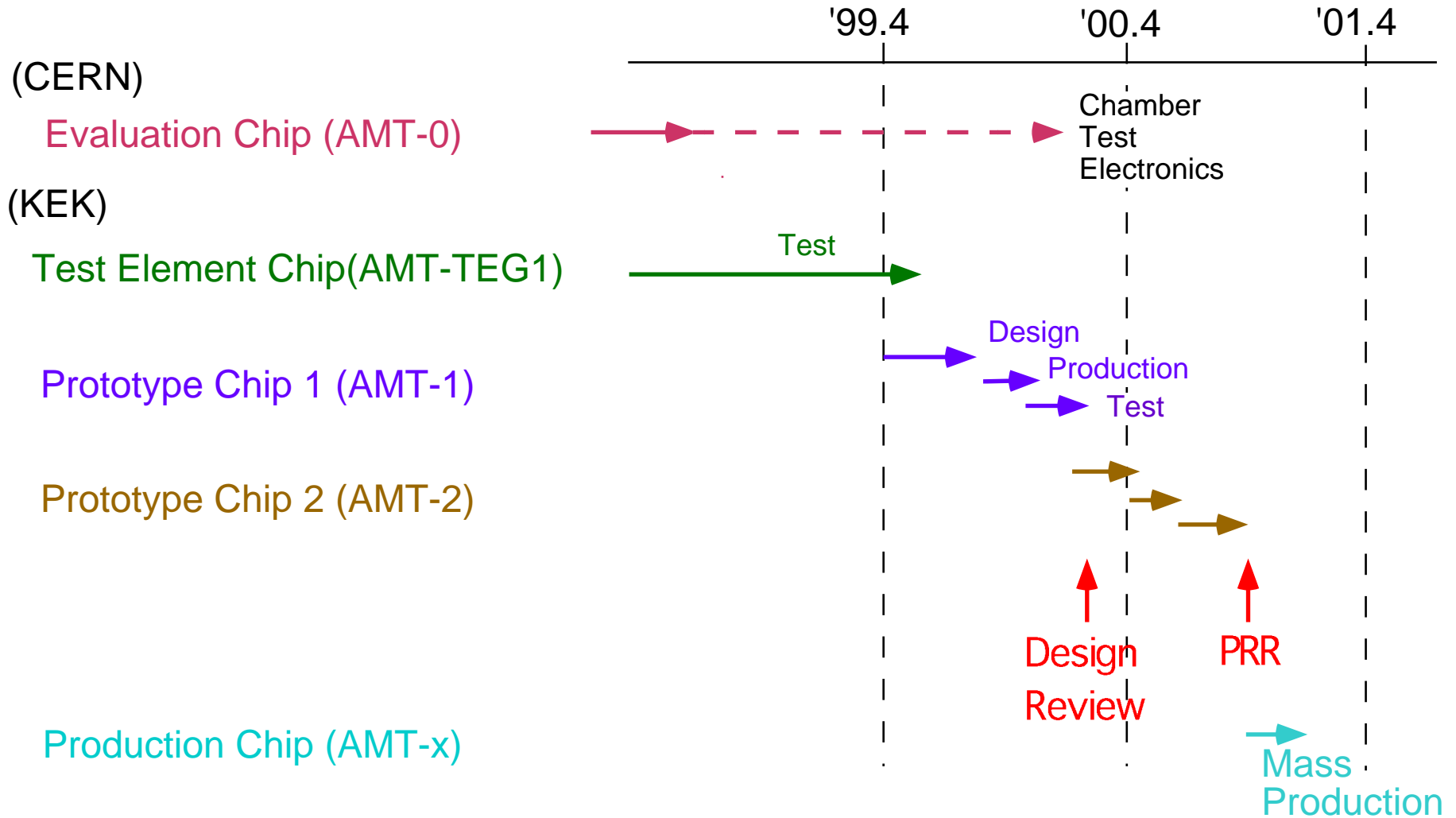
AMT-TEG1 Differential Nonlinearity



AMT-TEG1 Integral Nonlinearity



AMT Schedule



Summary

- ❑ Fundamental performance for the AMT was tested and found to fulfil the requirements.
- ❑ Neutron irradiation of the chip was done, and measurements will be done soon..
- ❑ AMT-1 design will be finished around this summer.